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**PRODUCT/PROCESS CHANGE NOTIFICATION**  
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**08-AUG-2001**

**SUBJECT: ON Semiconductor Product/Process Change Notification #11628**

**TITLE: Assembly/Test Site Change For SC88 Package**

**EFFECTIVE DATE: 07-Oct-2001**

**AFFECTED CHANGE CATEGORY:**

**On Semiconductor Assembly Site**

**On Semiconductor Test Site**

**AFFECTED PRODUCT DIVISION: Bipolar Discretes Products Div**

**ADDITIONAL RELIABILITY DATA:** Available

Contact your local ON Semiconductor Sales Office or Laura Rivers <S20636@onsemi.com>

**SAMPLES:** Contact your local ON Semiconductor Sales Office or Ts Teo <[R10920@onsemi.com](mailto:R10920@onsemi.com)>

**FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:**

Contact Sales Office or Jake Lee <R14795@onsemi.com>

**DISCLAIMER:**

Initial Product/Process Change Notification (IPCN) -First Notification distributed to customers.  
Distributed at least 120 days from the effective date of the change.

Final Product/Process Change Notification (FPCN) -Final Notification completing the notification process. Distributed at least 60 days from the effective date of the change. ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact your local ON Semiconductor Sales Office.

**DESCRIPTION AND PURPOSE:**

Assembly and test qualification of SC88 manufacturing to SBN1, ON Semiconductor's factory in Malaysia. This change affects general purpose transistors, Bias Resistor Transistors/Digital transistors, Switching diodes. SBN1 has been both QS9000 certified and Automotive Engineering Council (AEC) qualified. SBN1 has been producing all the technologies listed above in various packages as ON Semiconductor's main facility, serving the customers worldwide for decades. There will be no change to the form, fit, and function of the devices. Device parameters will continue to meet all Data Book specifications, and reliability will continue to meet or exceed ON Semiconductor standards.



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**QUALIFICATION PLAN:**

<u>Test</u>	<u>Conditions</u>	<u>Sample size</u>
Temp Cycle	Air to Air, Ta=-65 to +150 degC, dwell greater than or equal to 10 mins, 1000 cycles	231
Autoclave	Ta=121 degC, RH= 100%, PSIg=15, 192 hrs.	231
H3TRB	V=80% of rated or 100V depending on whichever lower, Ta=85 C, RH= 85%, 1000 hrs.	231
IOL	Ta=25 C, delta Tj =>100 C, 2.0 minutes on/off, 15000 cycles	231

**RELIABILITY DATA SUMMARY:**

Reliability testing of SC88 BRT technology assembled and tested at SBN meets or exceeds the requirements set forth in the ON Semiconductor Product Introduction and Process Change Qualification 12MSB17722C(d). A copy of the full Reliability Report (ref # :ZM01405A, ZM011402) is available upon request.

**Reliability Tests and Results :**

Test device: MUN5115DW1T1

<u>Test Description</u>	<u>Result(504hrs),</u>	<u>Result(1008hrs)</u>
Temperature Cycle	0/231	0/231
Autoclave	0/231	0/231
H3TRB	0/231	0/231
IOL	0/231	0/231

**ELECTRICAL CHARACTERISTIC SUMMARY:**

Electrical characterization indicates parametric distribution remains unchanged with respect to electrical limit.

**CHANGED PART IDENTIFICATION:**

For site identification purpose, the date code character will be placed upright next to the device marking. Customers may receive these products manufactured starting with date code T (Oct 2001) or later.

**AFFECTED DEVICE LIST (WITHOUT SPECIALS):**

**PART**

- BC846BDW1T1
- BC846BPDW1T1
- BC847BDW1T1
- BC847BPDW1T1
- BC847CDW1T1
- BC847CPDW1T1
- BC848BDW1T1
- BC848BPDW1T1
- BC848CDW1T1
- BC848CPDW1T1
- BC856BDW1T1
- BC857BDW1T1
- BC857CDW1T1
- BC858BDW1T1
- BC858CDW1T1



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MBD110DWT1  
MBD330DWT1  
MBD54DWT1  
MBD770DWT1  
MBT3904DW1T1  
MBT3904DW1T3  
MBT3906DW1T1  
MBT3906DW1T3  
MBT3906DW9T1  
MBT3906DW9T3  
MBT3946DW1T1  
MBT3946DW1T2  
MUN5111DW1T1  
MUN5112DW1T1  
MUN5113DW1T1  
MUN5114DW1T1  
MUN5115DW1T1  
MUN5116DW1T1  
MUN5130DW1T1  
MUN5131DW1T1  
MUN5132DW1T1  
MUN5133DW1T1  
MUN5134DW1T1  
MUN5135DW1T1  
MUN5136DW1T1  
MUN5137DW1T1  
MUN5211DW1T1  
MUN5212DW1T1  
MUN5213DW1T1  
MUN5214DW1T1  
MUN5215DW1T1  
MUN5215DW1T2  
MUN5216DW1T1  
MUN5216DW1T2  
MUN5230DW1T1  
MUN5231DW1T1  
MUN5232DW1T1  
MUN5233DW1T1  
MUN5234DW1T1  
MUN5235DW1T1  
MUN5236DW1T1  
MUN5237DW1T1  
MUN5311DW1T1  
MUN5312DW1T1  
MUN5312DW1T2  
MUN5312DW1T3  
MUN5313DW1T1  
MUN5314DW1T1  
MUN5315DW1T1  
MUN5316DW1T1  
MUN5316DW1T2  
MUN5330DW1T1  
MUN5331DW1T1  
MUN5332DW1T1  
MUN5333DW1T1  
MUN5334DW1T1



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MUN5335DW1T1  
NSR15TW1T2  
SSVBC847BDW1T1  
SSVBC847CDW1T1  
SSVMUN5313DW1T1